



EMI TEST REPORT

Test Report No. : 11255723H-B

Applicant : Sharp Corporation, Consumer Electronics Company,
Communication Systems Division

Type of Equipment : Smart Phone

Model No. : SHV35

FCC ID : APYHRO00235

Test standard : FCC Part 15 Subpart B 2015 Class B

Test Result : Complied

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2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.
6. This test report covers EMC technical requirements. It does not cover administrative issues such as Manual or non-EMC test related Requirements. (if applicable)

Date of test: April 21 and 22, 2016

**Representative
test engineer:**

Ken. Fujita

Ken Fujita
Engineer

Consumer Technology Division

Approved by :

Tsubasa Takayama

Tsubasa Takayama
Engineer

Consumer Technology Division



NVLAP LAB CODE: 200572-0

This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation.
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UL Japan, Inc.

Ise EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8999

Facsimile : +81 596 24 8124

13-EM-F0429

REVISION HISTORY

Original Test Report No.: 11255723H-B

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SECTION 1: Customer information

Company Name : Sharp Corporation, Consumer Electronics Company, Communication Systems Division
Address : 2-13-1 Iida Hachihonmatsu HigashiHiroshima-City, Hiroshima, 739-0192 Japan
Telephone Number : +81-82-420-1552
Facsimile Number : +81-82-420-1555
Contact Person : Hiroyuki Uwatoko

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Smart Phone
Model No. : SHV35
Serial No. : Refer to Section 4, Clause 4.2
Receipt Date of Sample : April 20, 2016
Country of Mass-production : Japan
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

2.2 Product description

Feature of EUT : SHV35 is WiMAX2+, Quad-band LTE(Band 1 / 3 / 17 / 26), Dual-band WCDMA(FDD I / V) & Quad-band GSM(850 / 900 / 1800 / 1900) Multi-mode Smart Phone.
The EUT has the function that NFC, Bluetooth and Wireless-LAN technology interface for establishing contact and transmitting data with certain device.
Clock frequencies in the system : CPU: 1.5168GHz (max)
Source oscillation: 19.2MHz, 27.12MHz(NFC), 27MHz(DTV), 96MHz(BT/WLAN)
The maximum frequency for radio use : 2480 MHz (Bluetooth 79ch)

SECTION 3: Test specification, procedures & results

3.1 Test specification

Test specification : FCC Part 15 Subpart B: 2015, final revised on November 23, 2015
*Some parts are effective on and after December 17, 2015 or December 23, 2015.
The revision does not affect the test specification applied to the EUT.

Title : FCC 47CFR Part15 Radio Frequency Device
Subpart B Unintentional Radiators

3.2 Procedures and results

Item	Test Procedure	Limits	Deviation	Worst margin	Result
Conducted emission	ANSI C63.4: 2014 7. AC power - line conducted emission measurements	Class B	N/A	[QP] 11.7 dB 0.17330 MHz, L [AV] 11.5 dB 0.17330 MHz, L	Complied
Radiated emission	ANSI C63.4: 2014 8. Radiated emission measurements	Class B	N/A	8.8 dB 599.773 MHz, Horizontal, QP	Complied

*Note: UL Japan, Inc's EMI Work Procedure 13-EM-W0420.

3.3 Addition to standard

No addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95 % using a coverage factor $k = 2$.

Frequency range	Conducted emission using AMN(LISN) (+dB)
0.009 – 0.15MHz	3.5 dB
0.15 – 30MHz	2.9 dB

Polarity	Radiated emission (Below 1GHz)			
	(3 m*)(+dB)		(10 m*)(+dB)	
	30 – 200 MHz	200 – 1000MHz	30 – 200 MHz	200 – 1000MHz
Horizontal	4.9 dB	5.2 dB	4.9 dB	5.0 dB
Vertical	4.6 dB	5.9 dB	5.0 dB	5.0 dB

Radiated emission				
(3 m*)(+dB)		(1 m*)(+dB)	(0.5 m*)(+dB)	(10 m*)(+dB)
1 – 6GHz	6 – 18GHz	10 – 26.5 GHz	26.5 – 40GHz	1 -18 GHz
5.1 dB	5.3 dB	5.1 dB	5.1 dB	5.3 dB

Conducted Emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test(3 m)

The data listed in this test report has enough margin, more than the site margin.

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Ise EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8999

Facsimile : +81 596 24 8124

3.5 Test Location

UL Japan, Inc. Ise EMC Lab. *NVLAP Lab. code: 200572-0
4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN
Telephone : +81 596 24 8999 Facsimile : +81 596 24 8124

	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	4.0 x 4.5 x 2.7m	4.0 x 4.5 m	-
No.6 measurement room	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	8.8 x 4.6 x 2.8m	2.4 x 2.4m	-
No.11 measurement room	-	6.2 x 4.7 x 3.0m	4.8 x 4.6m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test data, Test instruments, and Test set up

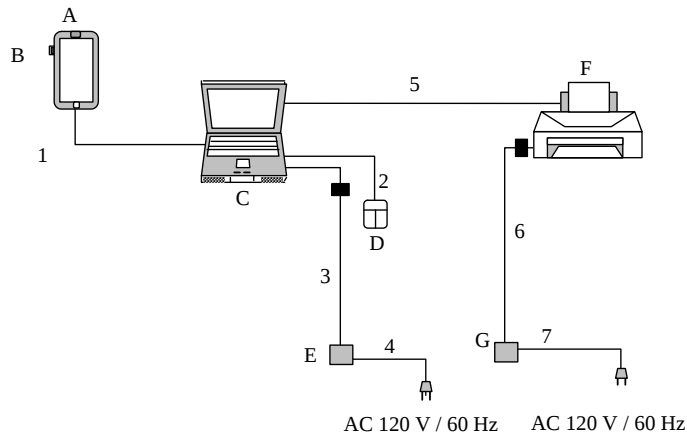
Refer to APPENDIX.

SECTION 4: Operation of E.U.T. during testing

4.1 Operating modes

The mode(s) : 1) USB Data Com Mode
The USB data is communicated between EUT and Personal computer (Pair of EUT).
2) Standby Mode
Standby state for USB communication.

4.2 Configuration and peripherals



■ : Ferrite core which has been standard on support equipment.

*Cabling and setup were taken into consideration and test data was taken under worse case conditions.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Smart Phone	SHV35	004401/11/575132/9	Sharp Corporation	EUT
B	microSD Memory Card	SD-MD008GA	None	TOSHIBA	-
C	Personal Computer	PP11L	CN-0D4571-48643-55V-1651	Dell	-
D	Mouse	M-BE55	LZE21450232	Logitech	-
E	AC Adapter(PC)	PA-1650-05D2	CN-0F7970-71615-561-14A1	Dell	-
F	Printer	895Cxi	SG8BL1W16V	Hewlett Packard	-
G	AC Adapter(Printer)	C4557-60004	C8K28B	Hewlett Packard	-

List of cables used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	USB Data Cable	0.95	Shielded	Shielded	-
2	Mouse Cable	0.72	Unshielded	Unshielded	-
3	AC Adaptor Cable (PC)	1.76	Unshielded	Unshielded	-
4	AC Power Cable (PC)	1.20	Unshielded	Unshielded	-
5	Parallel Cable	1.65	Shielded	Shielded	-
6	AC Adapter Cable (printer)	2.00	Unshielded	Unshielded	-
7	AC Power Cable (printer)	1.75	Unshielded	Unshielded	-

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SECTION 5: Conducted Emission

5.1 Operating environment

Test place	: No. 1 semi anechoic chamber
Temperature	: See data
Humidity	: See data

5.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0 m by 1.5 m, raised 0.8 m above the conducting ground plane.

The rear of tabletop was located 40 cm to the vertical conducting plane. The rear of EUT and its peripherals was aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80 cm from any other grounded conducting surface. EUT was located 80 cm from the LISN/AMN and excess AC cable was bundled in center. I/O cables that were connected to the other peripherals were bundled in center. They were folded back and forth forming a bundle 30 cm to 40 cm long and were hanged at a 40 cm height to the ground plane. Each EUT current-carrying power lead, except the ground (safety) lead, was individually connected through a LISN/AMN to the input power source. All unused 50 ohm connectors of the LISN/AMN were resistivity terminated in 50 ohm when not connected to the measuring equipment.

Photographs of the set up are shown in Appendix 3.

Frequency range	: 0.15 MHz - 30 MHz
EUT position	: Table top
EUT operation mode	: See Clause 4.1

5.3 Test procedure

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT within a semi anechoic chamber. The EUT was connected to a Line Impedance Stabilization Network (LISN)/ Artificial Mains network (AMN). An overview sweep with peak detection has been performed. The measurements have been performed with a quasi-peak detector and if required, with an average detector.

The conducted emission measurements were made with the following detector function of the test receiver.

Detector Type	: Quasi-Peak and CISPR AV
IF Bandwidth	: 9 kHz

5.4 Test result

Summary of the test results: Pass

Date: April 22, 2016

Test engineer: Ken Fujita

SECTION 6: Radiated Emission

6.1 Operating environment

Test place : No. 1 semi anechoic chamber
Temperature : See data
Humidity : See data

6.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0 m by 1.5 m, raised 0.8 m above the conducting ground plane.

The EUT was set on the center of the tabletop.

Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength.

Photographs of the set up are shown in Appendix 3.

6.3 Test conditions

Frequency range : 30 MHz - 200 MHz (Biconical antenna) / 200 MHz - 1000 MHz (Logperiodic antenna)
1000 MHz - 30 GHz (Horn antenna)
Test distance : 3 m
EUT position : Table top
EUT operation mode : See Clause 4.1

6.4 Test procedure

The height of the measuring antenna varied between 1 m and 4 m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver.

The radiated emission measurements were made with the following detector function of the Test Receiver.

Frequency	Below 1GHz	Above 1GHz *1)	
Instrument used	Test Receiver	Test Receiver	Spectrum Analyzer
IF Bandwidth	QP: BW 120kHz	PK: BW 1MHz, CISPR AV: BW 1MHz	PK: RBW: 1 MHz / VBW: 3 MHz AV *2): RBW: 1 MHz / VBW: 10 Hz

*1) The measurement data was adjusted to a 3 m distance using the following Distance Factor.

Distance Factor: $20 \times \log (3.4\text{m} / 3.0\text{m}) = 1.09 \text{ dB}$

Distance Factor: $20 \times \log (1.0\text{m} / 3.0\text{m}) = -9.5 \text{ dB}$

Distance Factor: $20 \times \log (0.5\text{m} / 3.0\text{m}) = -15.6 \text{ dB}$

*2) When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

6.5 Test result

Summary of the test results: Pass

Date: April 21, 2016

Test engineer: Ken Fujita

APPENDIX 1: Test data

Conducted Emission

DATA OF CONDUCTED EMISSION TEST

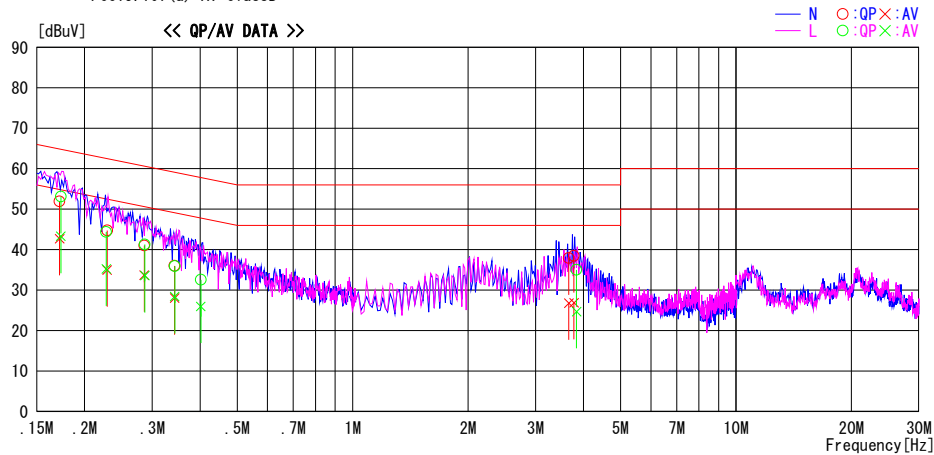
UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2016/04/22

Report No. : 11255723H

Temp./Humi. : 21deg. C / 58% RH
Engineer : Ken Fujita

Mode / Remarks : USB Data Com mode

LIMIT : FCC15.107(a) QP ClassB
FCC15.107(a) AV ClassB



Frequency [MHz]	Reading Level		Corr. Factor	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.17200	38.7	29.5	13.2	51.9	42.7	64.9	54.9	13.0	12.2	N	
0.22890	31.4	21.7	13.3	44.7	35.0	62.5	52.5	17.8	17.5	N	
0.28600	27.7	20.4	13.3	41.0	33.7	60.6	50.6	19.6	16.9	N	
0.34321	22.7	14.8	13.3	36.0	28.1	59.1	49.1	23.1	21.0	N	
3.66380	24.1	13.0	13.8	37.9	26.8	56.0	46.0	18.1	19.2	N	
3.77717	24.7	13.1	13.8	38.5	26.9	56.0	46.0	17.5	19.1	N	
0.17330	39.9	30.1	13.2	53.1	43.3	64.8	54.8	11.7	11.5	L	
0.22774	31.1	21.9	13.3	44.4	35.2	62.5	52.5	18.1	17.3	L	
0.28710	28.0	20.3	13.3	41.3	33.6	60.6	50.6	19.3	17.0	L	
0.34359	22.6	15.1	13.3	35.9	28.4	59.1	49.1	23.2	20.7	L	
0.40200	19.3	12.7	13.3	32.6	26.0	57.8	47.8	25.2	21.8	L	
3.83840	21.2	10.9	13.8	35.0	24.7	56.0	46.0	21.0	21.3	L	

CHART : WITH FACTOR, Peak hold data. CALCULATION : RESULT = READING + C.F (LISN + ATTEN. + CABLE)
Except for the above table : adequate margin data below the limits.

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

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Conducted Emission

DATA OF CONDUCTED EMISSION TEST

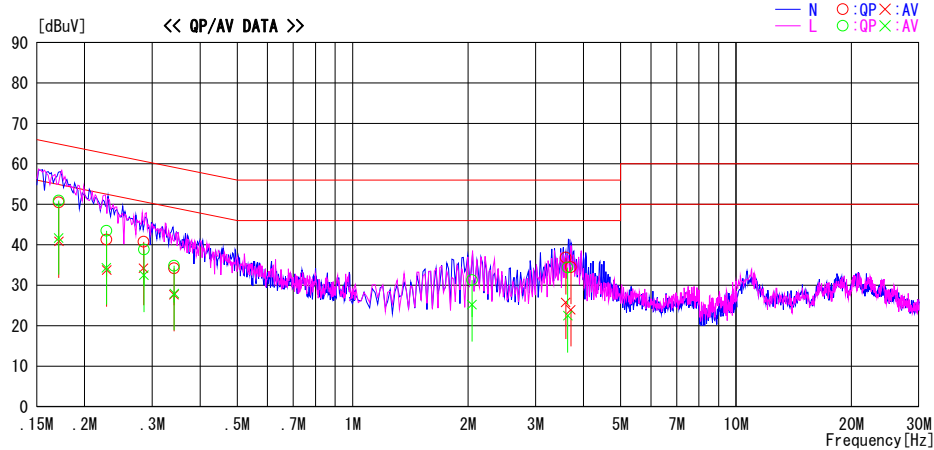
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Date : 2016/04/22

Report No. : 11255723H

Temp./Humi. : 21deg. C / 58% RH
Engineer : Ken Fujita

Mode / Remarks : Standby mode

LIMIT : FCC15.107(a) QP ClassB
FCC15.107(a) AV ClassB



Frequency [MHz]	Reading		Level	Corr. Factor	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]			QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.17120	37.3	27.7	13.2		50.5	40.9	64.9	54.9	14.4	14.0	N	
0.22824	28.0	20.5	13.3		41.3	33.8	62.5	52.5	21.2	18.7	N	
0.28480	27.4	20.9	13.3		40.7	34.2	60.7	50.7	20.0	16.5	N	
0.34216	20.9	14.4	13.3		34.2	27.7	59.2	49.2	25.0	21.5	N	
3.59600	23.0	12.0	13.8		36.8	25.8	56.0	46.0	19.2	20.2	N	
3.70820	20.7	10.2	13.8		34.5	24.0	56.0	46.0	21.5	22.0	N	
0.17106	37.7	28.5	13.2		50.9	41.7	64.9	54.9	14.0	13.2	L	
0.22800	30.2	21.0	13.3		43.5	34.3	62.5	52.5	19.0	18.2	L	
0.28540	25.5	19.2	13.3		38.8	32.5	60.7	50.7	21.9	18.2	L	
0.34240	21.5	14.7	13.3		34.8	28.0	59.1	49.1	24.3	21.1	L	
2.04720	17.8	11.7	13.5		31.3	25.2	56.0	46.0	24.7	20.8	L	
3.63800	20.6	8.7	13.8		34.4	22.5	56.0	46.0	21.6	23.5	L	

CHART : WITH FACTOR, Peak hold data. CALCULATION : RESULT = READING + C.F (LISN + ATTEN. + CABLE)
Except for the above table : adequate margin data below the limits.

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission (Below 1GHz)

DATA OF RADIATED EMISSION TEST

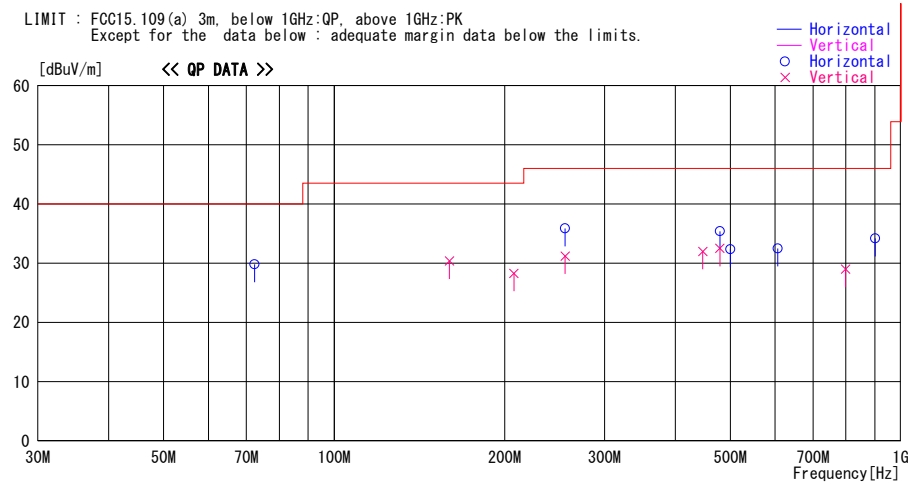
UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2016/04/21

Report No. : 11255723H

Temp./Humi. : 21deg. C / 51% RH
Engineer : Ken Fujita

Mode / Remarks : USB Data Com Mode

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
Except for the data below : adequate margin data below the limits.



Frequency	Reading	DET	Antenna	Loss&	Level	Angle	Height	Polar.	Limit	Margin	Comment
			Factor	Gain							
[MHz]	[dBuV]		[dB/m]	[dB]	[dBuV/m]	[Deg]	[cm]		[dBuV/m]	[dB]	
72.385	54.7	QP	6.3	-31.2	29.8	285	265	Hori.	40.0	10.2	
159.770	45.1	QP	15.2	-29.9	30.4	180	100	Vert.	43.5	13.1	
207.704	46.1	QP	11.6	-29.4	28.3	330	100	Vert.	43.5	15.2	
255.630	52.0	QP	12.6	-28.7	35.9	207	117	Hori.	46.0	10.1	
255.633	47.3	QP	12.6	-28.7	31.2	234	100	Vert.	46.0	14.8	
447.358	42.2	QP	16.6	-26.8	32.0	0	157	Vert.	46.0	14.0	
479.313	41.9	QP	17.2	-26.6	32.5	324	149	Vert.	46.0	13.5	
479.311	44.8	QP	17.2	-26.6	35.4	124	145	Hori.	46.0	10.6	
500.410	41.2	QP	17.6	-26.4	32.4	266	154	Hori.	46.0	13.6	
607.125	39.0	QP	19.1	-25.6	32.5	151	102	Hori.	46.0	13.5	
798.684	32.8	QP	20.8	-24.6	29.0	261	117	Vert.	46.0	17.0	
900.740	36.0	QP	21.9	-23.7	34.2	331	100	Hori.	46.0	11.8	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-200MHz:BICONICAL, 200MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION : RESULT = READING + ANT FACTOR + LOSS & GAIN (CABLE - GAIN (AMP) + D. FACTOR)

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission (Below 1GHz)

DATA OF RADIATED EMISSION TEST

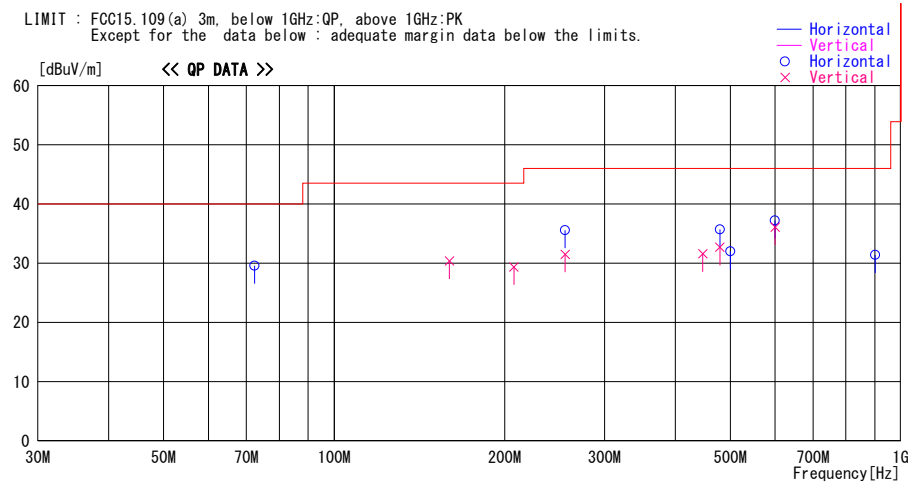
UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2016/04/21

Report No. : 11255723H

Temp./Humi. : 21deg. C / 51% RH
Engineer : Ken Fujita

Mode / Remarks : Standby Mode

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
Except for the data below : adequate margin data below the limits.



Frequency	Reading	DET	Antenna Factor	Loss & Gain	Level	Angle	Height	Polar.	Limit	Margin	Comment
[MHz]	[dBuV]		[dB/m]	[dB]	[dBuV/m]	[Deg]	[cm]		[dBuV/m]	[dB]	
72.385	54.5	QP	6.3	-31.2	29.6	293	267	Hori.	40.0	10.4	
159.770	45.1	QP	15.2	-29.9	30.4	174	100	Vert.	43.5	13.1	
207.702	47.2	QP	11.6	-29.4	29.4	349	100	Vert.	43.5	14.1	
255.630	51.7	QP	12.6	-28.7	35.6	212	117	Hori.	46.0	10.4	
255.633	47.6	QP	12.6	-28.7	31.5	223	146	Vert.	46.0	14.5	
447.358	41.8	QP	16.6	-26.8	31.6	0	163	Vert.	46.0	14.4	
479.313	42.1	QP	17.2	-26.6	32.7	337	146	Vert.	46.0	13.3	
479.311	45.1	QP	17.2	-26.6	35.7	121	144	Hori.	46.0	10.3	
500.395	40.8	QP	17.6	-26.4	32.0	265	154	Hori.	46.0	14.0	
599.773	43.9	QP	19.0	-25.7	37.2	227	130	Hori.	46.0	8.8	
599.733	42.8	QP	19.0	-25.7	36.1	350	100	Vert.	46.0	9.9	
900.692	33.2	QP	21.9	-23.7	31.4	266	125	Hori.	46.0	14.6	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-200MHz:BICONICAL, 200MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION : RESULT = READING + ANT FACTOR + LOSS & GAIN (CABLE - GAIN (AMP) + D. FACTOR)

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission (Above 1GHz)

DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2016/4/21

Report No. : 11255723H

Temp./Humi. : 21deg. C / 51% RH
Engineer : Ken Fujita

Mode / Remarks : USB Data Com Mode

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV

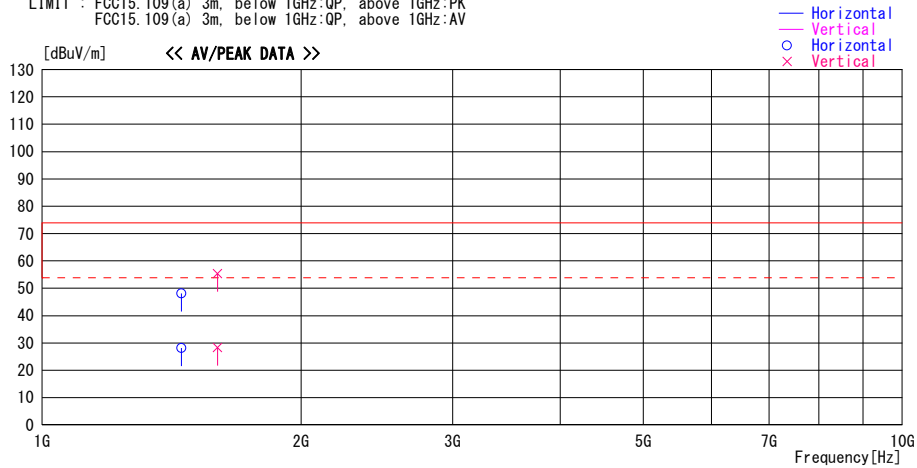


CHART: WITH FACTOR ANT TYPE: -30MHz: LOOP, 30-200MHz: BICONICAL, 200MHz-1000MHz: LOGPERIODIC, 1000MHz-: HORN
CALCULATION : RESULT = READING + ANT FACTOR + LOSS & GAIN (CABLE - GAIN (AMP) + D. FACTOR)

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

*The test was performed to 30 GHz.

Radiated Emission (Above 1GHz)

DATA OF RADIATED EMISSION TEST

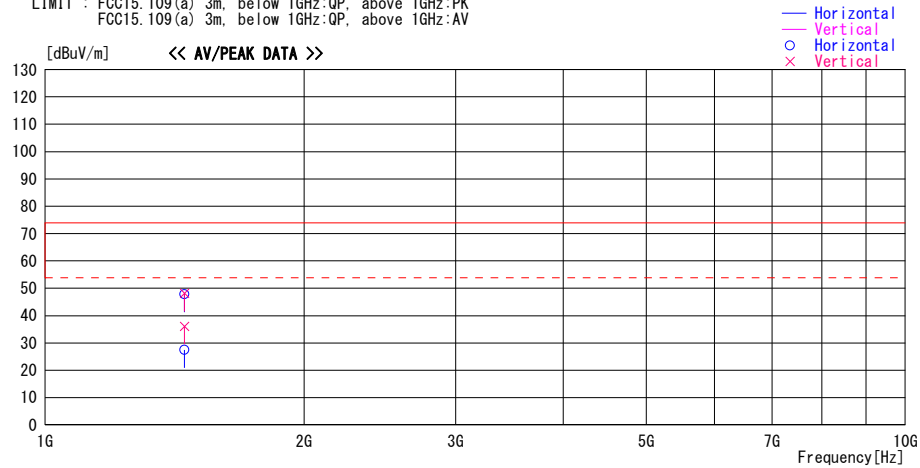
UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2016/4/21

Report No. : 11255723H

Temp./Humi. : 21deg. C / 51% RH
Engineer : Ken Fujita

Mode / Remarks : Standby Mode

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency	Reading	DET	Antenna Factor	Loss & Gain	Level	Angle	Height	Polar.	Limit	Margin	Comment
[MHz]	[dBuV]		[dB/m]	[dB]	[dBuV/m]	[Deg]	[cm]		[dBuV/m]	[dB]	
1452.376	55.8	PK	25.2	-33.2	47.8	359	303	Hori.	73.9	26.1	
1452.376	56.1	PK	25.2	-33.2	48.1	26	100	Vert.	73.9	25.8	
1452.376	44.1	AV	25.2	-33.2	36.1	26	100	Vert.	53.9	17.8	
1452.376	35.4	AV	25.2	-33.2	27.4	359	303	Hori.	53.9	26.5	

CHART: WITH FACTOR ANT TYPE: -30MHz: LOOP, 30-200MHz: BICONICAL, 200MHz-1000MHz: LOGPERIODIC, 1000MHz-: HORN
CALCULATION : RESULT = READING + ANT FACTOR + LOSS & GAIN (CABLE - GAIN (AMP) + D. FACTOR)

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

*The test was performed to 30 GHz.

APPENDIX 2: Test instruments

EMI Test Instruments

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MAEC-01	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 10m	DA-06881	RE/CE	2015/09/19 * 12
MOS-27	Thermo-Hygrometer	CUSTOM	CTH-201	A08Q26	RE/CE	2016/01/21 * 12
MJM-25	Measure	KOMELON	KMC-36	-	RE/CE	-
COTS-MEMI	EMI measurement program	TSJ	TEPTO-DV	-	RE/CE	-
MTR-09	EMI Test Receiver	Rohde & Schwarz	ESU26	100412	RE/CE	2015/06/08 * 12
KBA-05	Biconical Antenna	Schwarzbeck	BBA9106	2513	RE	2015/11/02 * 12
MLA-20	Logperiodic Antenna(200-1000MHz)	Schwarzbeck	VUSLP9111B	911B-189	RE	2016/01/30 * 12
MAT-08	Attenuator(6dB)	Weinschel Corp	2	BK7971	RE	2015/11/10 * 12
MCC-02	Coaxial Cable	Suhner/storm/Agilent/T SJ	-	-	RE	2015/09/29 * 12
MPA-19	Pre Amplifier	MITEQ	MLA-10K01-B01-35	1237616	RE	2016/02/25 * 12
MMM-03	Digital Tester	Fluke	FLUKE 26-3	78030621	RE/CE	2015/08/19 * 12
MHA-05	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	253	RE	2015/05/18 * 12
MCC-165	Microwave Cable	Junkosha	MWX221	1203S213(1m) / 1311S166(5m)	RE	2015/11/10 * 12
MLS-23	LISN(AMN)	Schwarzbeck	NSLK8127	8127-729	CE(EUT)	2015/07/10 * 12
MLS-25	LISN(AMN)	Schwarzbeck	NSLK8127	8127-731	CE(AE)	2015/07/17 * 12
MTA-30	Terminator	TME	CT-01	-	CE	2016/01/15 * 12
MCC-03	Coaxial Cable	Fujikura/Suhner/TSJ	5D-2W(20m)/3D-2W(7.5m)/RG400u(1.5m)/RFM-E421(Switcher)	- /01068(Switcher)	CE	2015/09/29 * 12
MAT-64	Attenuator(13dB)	JFW Industries, Inc.	50FP-013H2 N	-	CE	2016/01/14 * 12
MHA-01	Horn Antenna 18-26.5GHz	EMCO	3160-09	1266	RE	2015/06/06 * 12
MPA-01	Pre Amplifier	Agilent	8449B	3008A01671	RE	2016/02/26 * 12
MHA-03	Horn Antenna 26.5-40GHz	EMCO	3160-10	1150	RE	2015/06/06 * 12
MCC-54	Microwave Cable	Suhner	SUCOFLEX101	2873(1m) / 2876(5m)	RE	2016/03/18 * 12
MPA-03	Microwave System Power Amplifier	Agilent	83050A	3950M00205	RE	2015/06/02 * 12
MSA-10	Spectrum Analyzer	Agilent	E4448A	MY46180655	RE	2016/02/24 * 12

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item:

CE: Conducted Emissions

RE: Radiated Emissions

UL Japan, Inc.

Ise EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8999

Facsimile : +81 596 24 8124